Application/Control No. O9/831,930 Examiner Jinhee J Lee Applicant(s)/Patent Under Reexamination WENDT ET AL. Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY De Nicolo, Maurilio Tazio 379/413 09-2000 Α US-6,115,468 US-В С US-D US-Ε US-F US-US-G н US-US-1 J US-Κ US-

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